

Notice of References Cited	Application/Control No. 10/002,393		Applicant(s)/Patent Under Reexamination ISHIDA ET AL.	
	Examiner Nathan W. Ha		Art Unit 2814	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,750,473 B2	06-2004	Amundson et al.	257/40
*	B	US-6,872,973 B1	03-2005	Koyama et al.	257/59
*	C	US-6,545,291	04-2003	Amundson et al.	257/40
*	D	US-6,300,988 B1	10-2001	Ishihara et al.	349/43
*	E	US-2006/0046358 A1	03-2006	Yamazaki et al.	438/149
*	F	US-6,420,200	07-2002	Yamazaki et al.	438/30
*	G	US-2002/0044109 A1	04-2002	Kimura, Mutsumi	345/76
*	H	US-6,819,374 B2	11-2004	Sekiguchi, Kanetaka	349/106
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2005277017 A	10-2005	Japan	KAMATA et al.	
	O	JP 2005229084 A	08-2005	Japan	O et al.	
	P	JP 2004146430 A	05-2004	Japan	HIRAI, KATSURA	
	Q	JP 2003282883 A	10-2003	Japan	KAMATA et al.	
	R	WO 9966540 A2	12-1999	World Intellect	JACKSON et al.	
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.